

<b>Notice of References Cited</b>	Application/Control No. 10/767,614	Applicant(s)/Patent Under Reexamination OGAWA, HIDEHIKO	
	Examiner Thomas D. Lee	Art Unit 2624	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,798,845	08-1998	Baek et al.	358/434
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
	K	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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